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Assignee:

Nanometrics Incorporated

TC 2800 MAIL ROOM

Title:

Apparatus And Method For The Measurement Of Diffracting Structures

Serial No.:

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COMMISSIONER FOR PATENTS

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**SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT
UNDER 37 CFR § 1.97(b)**

Dear Sir:

Pursuant to 37 C.F.R. § 1.56, § 1.97 and § 1.98, the document listed on the accompanying PTO Form-1449 is called to the attention of the Examiner for the above patent application. A copy of this document is enclosed.

Citation of this document shall not be construed as:

1. an admission that the document is necessarily prior art with respect to the instant invention;
2. a representation that a search has been made; or
3. an admission that the information cited herein is, or is considered to be, material to patentability as defined in § 1.56(b).

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, Washington, D.C. 20231, on June 27, 2001.

Michael J. Halbert 6-27-01
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Respectfully submitted,

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